Depth Sensors and 3D Vision

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Deadline for manuscript
submissions:
closed (20 December 2018)

Message from the Guest Editor

This Special Issue seeks innovative work to explore new hardware and software solutions for the generation and analysis of depth data, including representation models, machine learning approaches, datasets, and benchmarks.

The particular topics of interest include, but are not limited to:

- Depth acquisition techniques
- Depth data processing
- Analysis of depth data
- Fusion of depth data with other modalities
- From and to depth domain translation
- 3D scene reconstruction
- 3D shape modeling and retrieval
- 3D object recognition
- 3D biometrics
- 3D imaging for cultural heritage applications
- Point cloud modelling and processing
- Human action recognition on depth data
- Biomedical applications of depth data
- Other applications of depth data analysis
- Depth datasets and benchmarks
- Depth data visualization

For further reading, please follow the link at: http://www.mdpi.com/journal/sensors/special_issues/ Depth_Sensors_3D_Vision

Special Issue

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Message from the Editor-in-Chief

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